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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Application Number	Unknown
Filing Date	Unknown
First Named Inventor:	WOHLMUTH, Walter A.
Examiner name: Unknown	GROUP: Unknown
Attorney Docket Number	**TRQ-00004**

Sheet 1 of 1

U.S. PUBLISHED PATENT APPLICATIONS

Examiner Initials*	Cited No. [1]	U.S. Patent Document Number	Kind Code [2] *(if known)*	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Info. Appear
	A01	2002-0171076	A1	Danzilio	11/21/02	

U.S. PATENT DOCUMENTS

Examiner Initials*	Cited No. [1]	U.S. Patent Document Number	Kind Code [2] *(if known)*	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Info. Appear
	A02	6,242,293	B1	Danzilio	6/5/01	
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	Ko, Dae-Hong and Robert Sinclair, "In-situ dynamic high-resolution transmission electron microscopy: application to Pt/GaAs interfacial reactions," Ultramicroscopy, 54, pp. 166-178 (1994)
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EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

[1] Unique citation designation number. [2] See attached Kinds of U.S. Patent Documents. [3] Enter Office that issued the document by the two-letter code (WIPO Standard ST.3). [4] For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. [5] Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. [6] Applicant is to place a check mark here if English language Translation is attached.